

Description

The HFQD19N10LTM uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge. It can be used in a wide variety of applications.

General Features

V_{DS} =100V,I_D =15A

R_{DS(ON)} <112m Ω @ V_{GS}=10V

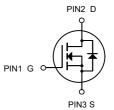
Application

Power switch

DC/DC converters



(DPAK)



N-Channel MOSFET

Package Marking and Ordering Information

Product ID	Pack	Brand	Qty(PCS)
HFQD19N10LTM	TO-252-2L(DPAK)	HXY MOSFET	2500

Absolute Maximum Ratings (Tc=25°Cunless otherwise noted)

Symbol	Parameter	Rating	Units		
Vds	Drain-Source Voltage	100	V		
Vgs	Gate-Source Voltage	±20	V		
I _D @T _C =25°C	Continuous Drain Current, V _{GS} @ 10V ¹	15	А		
I _D @Tc=100°C	Continuous Drain Current, V _{GS} @ 10V ¹	7.7	А		
I _D @T _A =25°C	Continuous Drain Current, V _{GS} @ 10V ¹	Continuous Drain Current, V _{GS} @ 10V ¹ 3			
I₀@T _A =70°C	Continuous Drain Current, V _{GS} @ 10V ¹	Continuous Drain Current, V_{GS} @ $10V^1$ 2.4			
Ідм	Pulsed Drain Current ²	24	А		
EAS	Single Pulse Avalanche Energy ³	6.1	mJ		
las	Avalanche Current	11			
P _D @T _C =25°C	Total Power Dissipation ³	34.7	W		
P _D @T _A =25°C	Total Power Dissipation ³	2	W		
Тѕтс	Storage Temperature Range	-55 to 150	°C		
TJ	Operating Junction Temperature Range	-55 to 150	°C		
Reja	Thermal Resistance Junction-ambient ¹	62	°C/W		
Rejc	Thermal Resistance Junction-Case ¹	3.6	°C/W		



N-Channel Enhancement Mode MOSFET

Symbol	ol Parameter Conditions		Min.	Тур.	Max.	Unit
BVDSS	Drain-Source Breakdown Voltage	V _{GS} =0V , I _D =250uA	100			V
₽BVpss/₽Tj	BVDSS Temperature Coefficient	Reference to 25°C , I _D =1mA		0.098		V/°C
_		V _{GS} =10V , I _D =10A		100	112	mΩ
RDS(ON)	Static Drain-Source On-Resistance ²	e ² V _{GS} =4.5V , I _D =8A		117	130	mΩ
VGS(th)	Gate Threshold Voltage		1.0		2.5	V
		V _{GS} =V _{DS} , I _D =250uA				
₿V _{GS(th)}	V _{GS(th)} Temperature Coefficient			-4.57		mV/°C
		V _{DS} =80V , V _{GS} =0V , T _J =25°C			1	
DSS	Drain-Source Leakage Current	V _{DS} =80V , V _{GS} =0V , T _J =55°C			5	uA
Igss	Gate-Source Leakage Current	V _{GS} =±20V , V _{DS} =0V			±100	nA
gfs	Forward Transconductance	V _{DS} =5V , I _D =10A		13		S
Rg	Gate Resistance	V _{DS} =0V , V _{GS} =0V , f=1MHz		2		Ω
Qg	Total Gate Charge (10V)			26.2		
Qgs	Gate-Source Charge	V _{DS} =80V , V _{GS} =10V , I _D =10A		4.6		nC
Qgd	Gate-Drain Charge			5.1		
Td(on)	Turn-On Delay Time			4.2		
Tr	Rise Time	──V _{DD} =50V,V _{GS} =10V, Rg=3.3		8.2		ns
Td(off)	Turn-Off Delay Time	ID=10A		35.6		
Tf	Fall Time			9.6		
Ciss	Input Capacitance			1535		
Coss	Output Capacitance	V _{DS} =15V , V _{GS} =0V , f=1MHz		60		pF
Crss	Reverse Transfer Capacitance			37		
ls	Continuous Source Current ^{1,5}				12	Α
lsм	Pulsed Source Current ^{2,5}	──V _G =V _D =0V , Force Current			24	Α
Vsd	Diode Forward Voltage ²	V _{GS} =0V , I _S =1A , T _J =25°C			1.2	V
trr	Reverse Recovery Time			37		nS
Qrr	Reverse Recovery Charge	IF=10A , dI/dt=100A/μs , Tյ=25℃		27.3		nC
			1	1		l

Electrical Characteristics (TJ=25°C, unless otherwise noted)

Note :

1. The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.

2.The data tested by pulsed , pulse width \leq 300us , duty cycle \leq 2%

3.The EAS data shows Max. rating . The test condition is VDD=25V,VGS=10V,L=0.1mH,IAS=11A

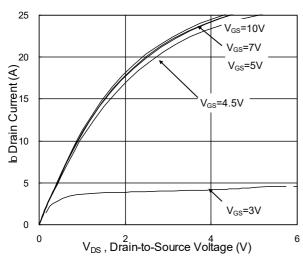
4.The power dissipation is limited by 150°C junction temperature

5 .The data is theoretically the same as ID and IDM, in real applications, should be limited by total power dissipation.



HFQD19N10LTM N-Channel Enhancement Mode MOSFET

Typical Characteristics





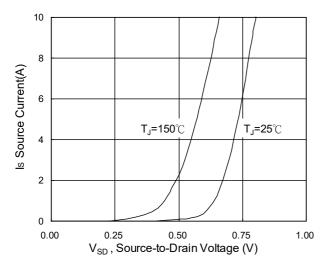


Fig.3 Forward Characteristics Of Reverse

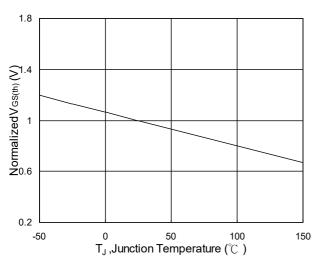


Fig.5 Normalized $V_{\text{GS}(\text{th})}$ vs. T_{J}

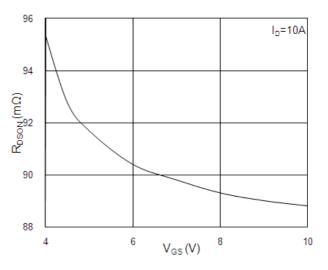


Fig.2 On-Resistance vs. Gate-Source

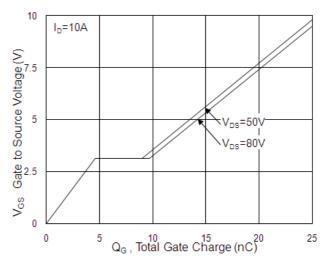


Fig.4 Gate-Charge Characteristics

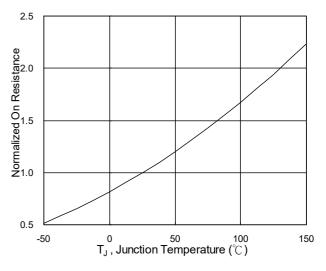
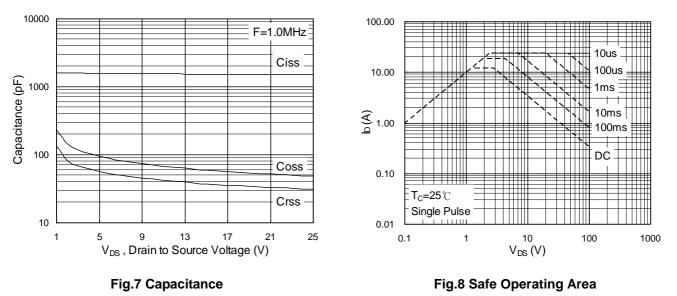


Fig.6 Normalized R_{DSON} vs. T_J



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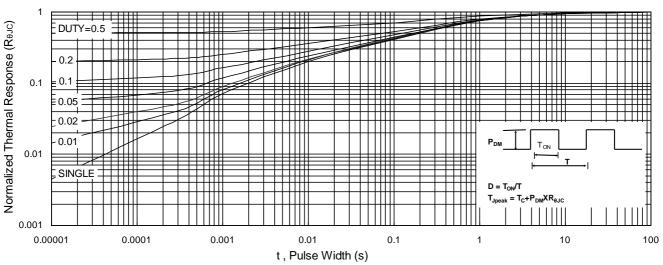


Fig.9 Normalized Maximum Transient Thermal Impedance

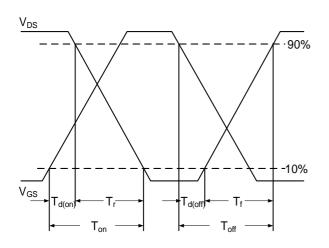


Fig.10 Switching Time Waveform

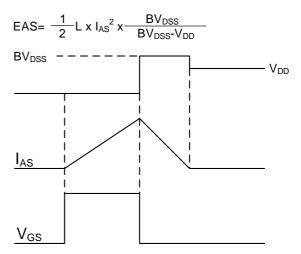
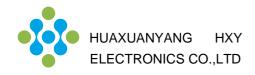
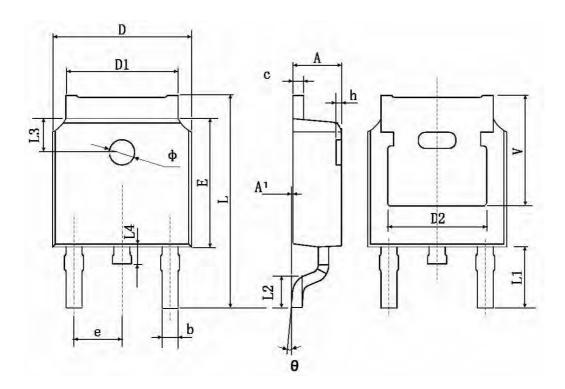


Fig.11 Unclamped Inductive Switching Waveform



TO-252-2L(DPAK) Package Information



Symbol	Dimensions In Millimeters		Dimensions In Inches		
	Min.	Max.	Min.	Max.	
А	2.200	2.400	0.087	0.094	
A1	0.000	0.127	0.000	0.005	
b	0.660	0.860	0.026	0.034	
с	0.460	0.580	0.018	0.023	
D	6.500	6.700	0.256	0.264	
D1	5.100	5.460	0.201	0.215	
D2	0.483 TYP.		0.190 TYP.		
E	6.000	6.200	0.236	0.244	
е	2.186	2.386	0.086	0.094	
L	9.800	10.400	0.386	0.409	
L1	2.900 TYP.		0.114 TYP.		
L2	1.400	1.700	0.055	0.067	
L3	1.600 TYP.		0.063 TYP.		
L4	0.600	1.000	0.024	0.039	
Φ	1.100	1.300	0.043	0.051	
θ	0°	8°	0 °	8°	
h	0.000	0.300	0.000	0.012	
V	5.350	TYP.	0.21	1 ТҮР.	



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